

1. SCOPE

1.1 Scope. This drawing describes device requirements for class B microcircuits in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices".

1.2 Part number. The complete part number shall be as shown in the following example:

| | | | |
|----------------|------------------------|-------------------------|--------------------------------|
| 5962-87669 | 01 | V | X |
| Drawing number | Device type (1.2.1) | Case outline (1.2.2) | Lead finish per MIL-M-38510 |

1.2.1 Device types. The device types shall identify the circuit function as follows:

| Device type | Generic number | Circuit function | Frequency |
|-------------|----------------|-------------------------------------|-----------|
| 01 | 82384-16 | Clock generator and reset interface | 16 MHz |
| 02 | 82384-12 | Clock generator and reset interface | 12.5 MHz |

1.2.2 Case outline. The case outline shall be as designated in appendix C of MIL-M-38510, and as follows:

| Outline letter | Case outline |
|----------------|---|
| V | D-6 (18-lead, 1/4" x 15/16") dual-in-line package |

1.3 Absolute maximum ratings.

| | |
|--|---------------------------------|
| Storage temperature range | -65°C to +150°C |
| Supply voltage with respect to V_{SS} | -0.5 V dc to +6.5 V dc |
| Voltage on other pins | -0.5 V dc to V_{CC} +0.5 V dc |
| Lead temperature (soldering, 10 seconds) | +275°C |
| Thermal resistance, junction-to-case (θ_{JC}) | 25°C/W |
| Junction temperature (T_J) | +138.8°C |
| Maximum power dissipation (P_D) | .55 W |

1.4 Recommended operating conditions.

| | |
|----------------------------------|-------------------|
| Case operating temperature range | -55°C to +125°C |
| Supply voltage (V_{CC}) | 5.0 V dc \pm 5% |

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2. APPLICABLE DOCUMENTS

2.1 Government specification and standard. Unless otherwise specified, the following specification and standard, of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

SPECIFICATION

MILITARY

MIL-M-38510 - Microcircuits, General Specification for.

STANDARD

MILITARY

MIL-STD-883 - Test Methods and Procedures for Microelectronics.

(Copies of the specification and standard required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.

3. REQUIREMENTS

3.1 Item requirements. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.

3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.

3.2.1 Terminal connections. The terminal connections shall be as specified on figure 1.

3.2.2 Logic diagram. The logic diagram shall be as specified on figure 2.

3.2.3 Case outline. The case outline shall be in accordance with 1.2.2 herein.

3.3 Electrical performance characteristics. Unless otherwise specified, the electrical performance characteristics are as specified in table I and apply over the full recommended case operating temperature range.

3.4 Marking. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the part number listed in 1.2 herein. In addition, the manufacturer's part number may also be marked as listed in 6.4 herein.

3.5 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in 6.4. The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall state that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.

3.6 Certificate of conformance. A certificate of conformance as required in MIL-STD-883 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.

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TABLE I. Electrical performance characteristics.

| Test | Symbol | Conditions $\frac{1}{-55^{\circ}\text{C} \leq T_C \leq +125^{\circ}\text{C}}$ $V_{CC} = 5\text{ V} \pm 5\%$ output trip level = 1.50 V | Group A subgroups | Device type | Limits | | Unit |
|--------------------------|-----------------|--|-------------------|-------------|----------------|----------|---------------|
| | | | | | Min | Max | |
| Input low voltage | V_{IL} | | 1, 2, 3 | A11 | | 0.8 | V |
| Input high voltage | V_{IH} | | 1, 2, 3 | A11 | 2.4 | | V |
| EFI input low voltage | V_{ILE} | | 1, 2, 3 | A11 | | 0.6 | V |
| RES input high voltage | V_{IHR} | | 1, 2, 3 | A11 | 2.6 | | V |
| RES hysteresis voltage | V_{YHS} 2/ | | 1, 2, 3 | A11 | 0.15 | | V |
| Output low voltage | V_{OL} | $I_{OL} = 5\text{ mA}$ | 1, 2, 3 | A11 | | 0.45 | V |
| Output high voltage | V_{OH} | $I_{OH} = -1\text{ mA}$ | 1, 2, 3 | A11 | 2.4 | | V |
| CLK2 output low voltage | V_{OLC2} | $I_{OL} = 8\text{ mA}$ | 1, 2, 3 | A11 | | 0.45 | V |
| CLK2 output high voltage | V_{OHC2} | $I_{OH} = -1\text{ mA}$ | 1, 2, 3 | A11 | $V_{CC} - 0.6$ | | V |
| CLK output low voltage | V_{OLC} | $I_{OL} = 5\text{ mA}$ | 1, 2, 3 | A11 | | 0.45 | V |
| CLK output high voltage | V_{OHC} | $I_{OH} = -1\text{ mA}$ | 1, 2, 3 | A11 | 4.0 | | V |
| Input leakage current | I_{LI} | $0\text{ V} \leq V_{IN} \leq V_{CC}$ | 1, 2, 3 | A11 | | ± 10 | μA |
| Supply current | I_{CC} | | 1, 2, 3 | A11 | | 105 | mA |

See footnotes at end of table.

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TABLE I. Electrical performance characteristics - Continued.

| Test | Symbol | Conditions ^{1/} -55°C ≤ T _C ≤ +125°C V _{CC} = 5 V ±5% output trip level = 1.50 V | Group A subgroups | Device type | Limits | | Unit |
|---------------------|------------------------------|--|----------------------|----------------|----------|-----|------|
| | | | | | Min | Max | |
| Input capacitance | C _I ^{2/} | F _c = 1 MHz | 4 | A11 | | 10 | pF |
| CLK2 period | t ₁ ^{2/} | | 9, 10, 11 | 01 02 | 31 40 | | ns |
| CLK2 high time | t _{2a} | 32 MHz 25 MHz ^{2/} at 2 V; C _L = 160 pF | 9, 10, 11 | 01 02 | 9 11 | | ns |
| CLK2 high time | t _{2b} | 32 MHz 25 MHz ^{2/} At (V _{CC} - 0.8 V); C _L = 160 pF | 9, 10, 11 | 01 02 | 5 7 | | ns |
| CLK2 low time | t _{3a} | 32 MHz 25 MHz ^{2/} At 2.0 V; C _L = 160 pF | 9, 10, 11 | 01 02 | 9 11 | | ns |
| CLK2 low time | t _{3b} | 32 MHz 25 MHz ^{2/} At 0.8 V; C _L = 160 pF | 9, 10, 11 | 01 02 | 7 9 | | ns |
| CLK2 fall time | t ₄ | From (V _{CC} - 0.8 V) to 0.8 V C _L = 160 pF | 9, 10, 11 | A11 | | 8 | ns |
| CLK2 rise time | t ₅ | From 0.8 V to (V _{CC} - 0.8 V) C _L = 160 pF | 9, 10, 11 | A11 | | 8 | ns |
| CLK delay from CLK2 | t ₆ | ^{3/} | 9, 10, 11 | A11 | 1 | 15 | ns |
| CLK fall time | t ₇ | From 3.5 V to 1 V | 9, 10, 11 | A11 | | 10 | ns |
| CLK rise time | t ₈ | From 1 V to 3.5 V | 9, 10, 11 | A11 | | 10 | ns |
| CLK low time | t ₉ | 16 MHz 12.5 MHz ^{2/} At 0.6 V; C _L = 160 pF | 9, 10, 11 | 01 02 | 15 15 | | ns |

See footnotes at end of table.

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TABLE I. Electrical performance characteristics - Continued.

| Test | Symbol | Conditions ^{1/} -55°C < T _C < +125°C V _{CC} = 5 V ±5% output trip level = 1.50 V | Group A subgroups | Device type | Limits | | Unit |
|----------------------------|-------------------------------|--|----------------------|----------------|----------|----------|------|
| | | | | | Min | Max | |
| CLK high time | t ₁₀ | 16 MHz 12.5 MHz ^{2/} At 3.8 V; C _L = 160 pF | 9, 10, 11 | 01 02 | 20 20 | | ns |
| EF1 to CLK2 delay | t ₁₁ | C _L = 160 pF | 9, 10, 11 | A11 | | 30 | ns |
| EF1 fall time | t ₁₂ ^{2/} | From 2.4 V to 0.6 V | 9, 10, 11 | A11 | | 3 | ns |
| EF1 rise time | t ₁₃ ^{2/} | From 0.6 V to 2.4 V | 9, 10, 11 | A11 | | 3 | ns |
| EF1 low time | t ₁₄ | 32 MHz 25 MHz ^{2/} At 0.6 V | 9, 10, 11 | 01 02 | 17 24 | | ns |
| EF1 high time | t ₁₅ | 32 MHz 25 MHz ^{2/} At 2.4 V | 9, 10, 11 | 01 02 | 15 22 | | ns |
| RES setup time to CLK2 | t ₁₆ | | 9, 10, 11 | A11 | 17 | | ns |
| RES hold time from CLK2 | t ₁₇ | | 9, 10, 11 | A11 | 0 | | ns |
| RESET delay from CLK2 | t ₁₈ | C _L = 125 pF | 9, 10, 11 | A11 | 4 | 18 | ns |
| ADS input delay | t ₁₉ | | 9, 10, 11 | 01 02 | 5 5 | 34 46 | ns |
| ADSO setup to CLK | t ₂₀ | C _L = 125 pF | 9, 10, 11 | A11 | 16 | | ns |
| ADSO hold from CLK | t ₂₁ ^{2/} | | 9, 10, 11 | A11 | 16 | | ns |

^{1/} See figures 3 and 4.

^{2/} Guaranteed if not tested.

^{3/} Capacitive loads on CLK2 and CLK should each be between 80 pF and 160 pF.

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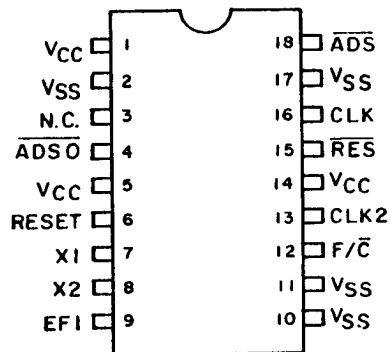


FIGURE 1. Terminal connections.

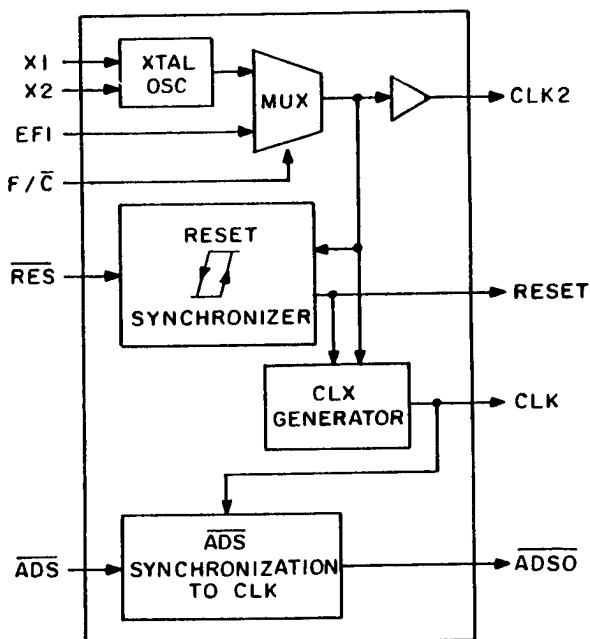


FIGURE 2. Logic diagram.

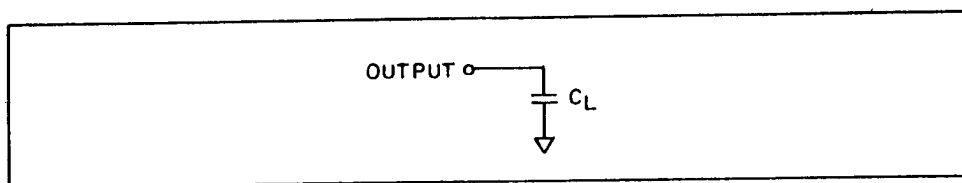


FIGURE 3. Output load.

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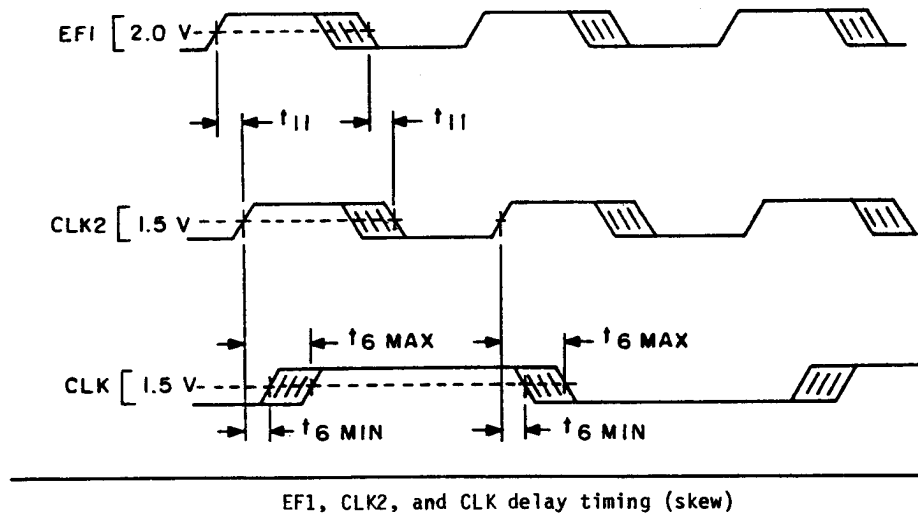
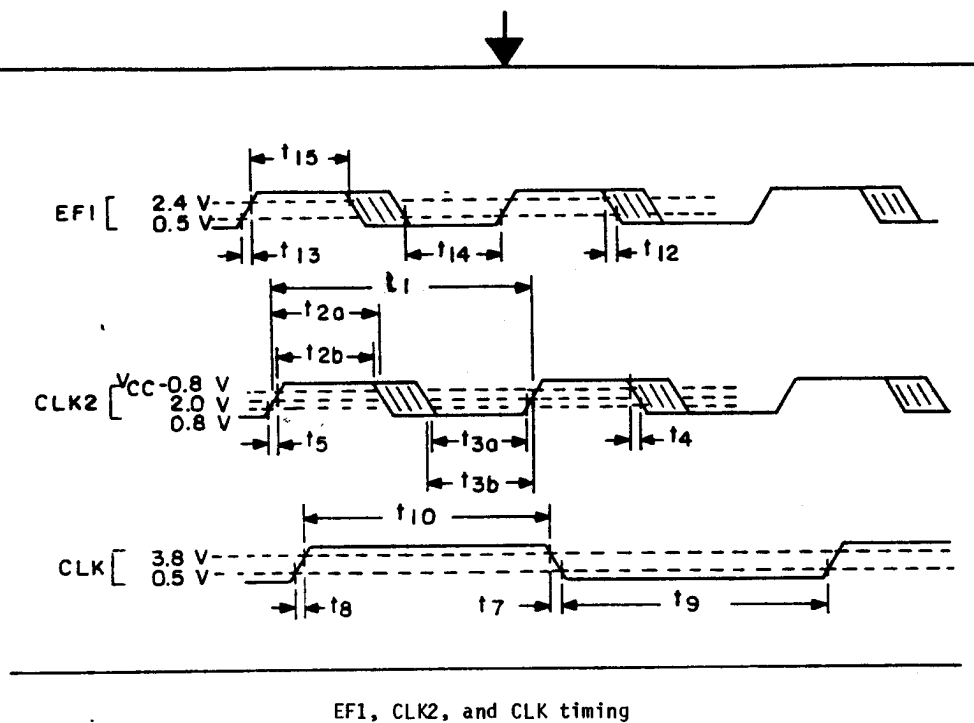
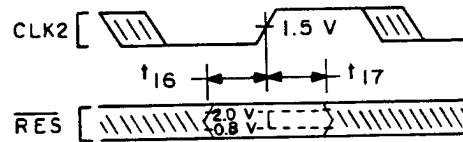


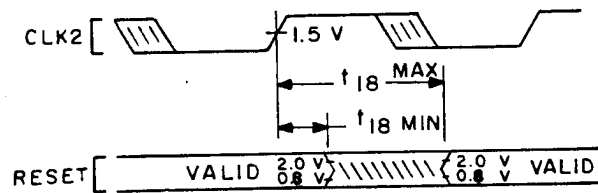
FIGURE 4. Waveforms.

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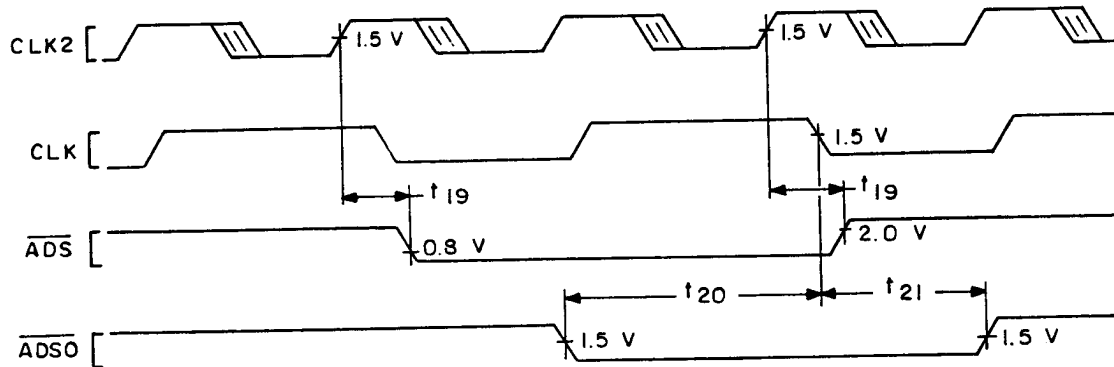
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RES input setup and hold timing



RESET output valid delay timing



ADS input delay and ADSO setup and hold timing

FIGURE 4. Waveforms - Continued.

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3.7 Notification of change. Notification of change to DESC-ECS shall be required in accordance with MIL-STD-883 (see 3.1 herein).

3.8 Verification and review. DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

4. QUALITY ASSURANCE PROVISIONS

4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).

4.2 Screening. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:

a. Burn-in test (method 1015 of MIL-STD-883).

(1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.5 herein).

(2) $T_A = +125^\circ\text{C}$, minimum.

b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.

4.3.1 Group A inspection.

a. Tests shall be as specified in table II herein.

b. Subgroups 5 and 6 in table I, method 5005 of MIL-STD-883 shall be omitted.

c. Subgroup 4 (C_{IN} measurement) shall be measured only for the initial test and after process or design changes which may affect capacitance.

4.3.2 Groups C and D inspections.

a. End-point electrical parameters shall be as specified in table II herein.

b. Steady-state life test (method 1005 of MIL-STD-883) conditions:

(1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.5 herein).

(2) $T_A = +125^\circ\text{C}$, minimum.

(3) Test duration: 1,000 hours, except as permitted by appendix B of MIL-M-38510 and method 1005 of MIL-STD-883.

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TABLE II. Electrical test requirements.

| | |
|--|--|
| MIL-STD-883 test requirements | Subgroups (per method 5005, table I) |
| Interim electrical parameters (method 5004) | --- |
| Final electrical test parameters (method 5004) | 1*, 2, 3, 7*, 8, 9, 10, 11 |
| Group A test requirements (method 5005) | 1, 2, 3, 7, 8, 9, 10, 11 |
| Groups C and D end-point electrical parameters (method 5005) | 2, 8(+125°C), 10 |
| Additional electrical subgroups for group C periodic inspections | --- |

*PDA applies to subgroups 1 and 7.

5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.

6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.

6.2 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.

6.3 Comments. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone 513-296-5375.

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6.4 Approved source of supply. An approved source of supply is listed herein. Additional sources will be added as they become available. The vendor listed herein has agreed to this drawing and a certificate of compliance (see 3.5 herein) has been submitted to DESC-ECS.

| Military drawing part number | Vendor CAGE number | Vendor similar part number <u>1/</u> | Replacement military specification part number |
|---------------------------------|--------------------------|--|--|
| 5962-8766901VX | 34649 | MD82384-16/B | --- |
| 5962-8766902VX | 34649 | MD82384-12/B | --- |

1/ Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE
number

34649

Vendor name
and address

Intel Corporation
5000 W. Williams Field Road
Chandler, AZ 85224

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